## Features

- Fast Read Access Time 45 ns
- Low Power CMOS Operation
  - 100 µA Max Standby
- 30 mA Max Active at 5 MHz
- JEDEC Standard Packages
  - 44-Lead PLCC
  - 40-Lead VSOP
- 5V  $\pm$  10% Power Supply
- High Reliability CMOS Technology
  - 2000V ESD Protection
  - 200 mA Latchup Immunity
- Rapid Programming Algorithm  $\mu$  50  $\mu s/Word$  (Typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Industrial Temperature Range

## 1. Description

The AT27C516 is a low-power, high-performance 524,288-bit one-time programmable read-only memory (OTP EPROM) organized 32K by 16 bits. It requires only one 5V power supply in normal read mode operation. Any word can be accessed in less than 45 ns, eliminating the need for speed reducing WAIT states. The by-16 organization make this part ideal for high-performance 16- and 32-bit microprocessor systems.

In read mode, the AT27C516 typically consumes 15 mA. Standby mode supply current is typically less than 10  $\mu A.$ 

The AT27C516 is available in industry-standard JEDEC-approved one-time programmable (OTP) plastic PLCC and VSOP packages. The device features two-line control  $(\overline{CE}, \overline{OE})$  to eliminate bus contention in high-speed systems.

With 32K word storage capability, the AT27C516 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's AT27C516 have additional features to ensure high quality and efficient production use. The Rapid Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50  $\mu$ s/word. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.



512K (32K x 16) OTP EPROM

# AT27C516

0362E-EPROM-1/08



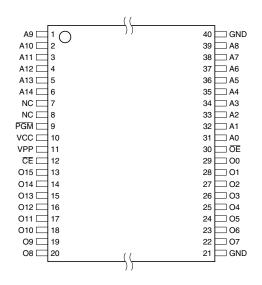


## 2. Pin Configurations

Pin Name	Function
A0 - A14	Addresses
O0 - O15	Outputs
CE	Chip Enable
ŌĒ	Output Enable
PGM	Program Strobe
NC	No Connect

Note: Both GND pins must be connected.

#### 2.1 40-lead VSOP (Type 1) Top View



#### 2.2 44-lead PLCC Top View

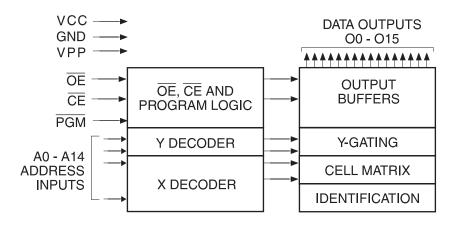
	_	013	014	015								□ A14	_
012	7	9	2	4	с	2	ō	44	43	42	41	<sup>4</sup> 39	A13
011	8						-					38	
O10 🗆	9											37	' 🗅 A11
O9 🗆	10	)										36	5 🗆 A10
O8 🗆	11	I										35	5 🗆 A9
GND 🗆	12	2										34	
NC 🗆	13	3										33	з∣⊐ис
07 🗆	14	ŀ										32	2 🗆 A8
O6 🗆	15	5										31	D A7
O5 🗆	16	6										30	D 🗅 A6
O4 🗆	17	18,	19	20	21	22	23	24	25	26	27	ფ <sup>29</sup>	) 🗆 A5
1		03 [	02 []	0 0			NC	A0	A1 🗆	A2	Ш	A4 🗆	_

Note: PLCC Package Pins 1 and 23 are Don't Connect.

### 3. System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu$ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

## 4. Block Diagram



## 5. Absolute Maximum Ratings\*

Temperature Under Bias	55°C to +125°C
Storage Temperature	65°C to +150°C
Voltage on Any Pin with Respect to Ground	2.0V to +7.0V <sup>(1)</sup>
Voltage on A9 with Respect to Ground	2.0V to +14.0V <sup>(1)</sup>
V <sub>PP</sub> Supply Voltage with Respect to Ground	2.0V to +14.0V <sup>(1)</sup>

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability

Note: 1. Minimum voltage is -0.6V DC which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V<sub>CC</sub> + 0.75V DC which may overshoot to +7.0 volts for pulses of less than 20 ns.





## 6. Operating Modes

Mode/Pin	CE	ŌĒ	PGM	Ai	V <sub>PP</sub>	Outputs
Read	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	Ai	Х	D <sub>OUT</sub>
Output Disable	Х	V <sub>IH</sub>	Х	х	Х	High Z
Standby	V <sub>IH</sub>	Х	Х	Х	X <sup>(5)</sup>	High Z
Rapid Program <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Ai	V <sub>PP</sub>	D <sub>IN</sub>
PGM Verify	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Ai	V <sub>PP</sub>	D <sub>OUT</sub>
PGM Inhibit	V <sub>IH</sub>	Х	Х	х	V <sub>PP</sub>	High Z
Product Identification <sup>(4)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	х	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A14 = V_{IL}$	V <sub>cc</sub>	Identification Code

Notes: 1. X can be  $V_{IL}$  or  $V_{IH}$ .

2. Refer to Programming Characteristics.

3.  $V_{H} = 12.0 \pm 0.5 V.$ 

 Two identifier bytes may be selected. All Ai inputs are held low (V<sub>IL</sub>), except A9 which is set to V<sub>H</sub> and A0 which is toggled low (V<sub>IL</sub>) to select the Manufacturer's Identification byte and high (V<sub>IH</sub>) to select the Device Code byte.

5. Standby  $V_{CC}$  current (I<sub>SB</sub>) is specified with  $V_{PP} = V_{CC}$ .  $V_{CC} > V_{PP}$  will cause a slight increase in I<sub>SB</sub>.

## 7. DC and AC Operating Conditions for Read Operation

	AT27	C516
	-45	-70
Industrial Operating Temperature (Case)	-40°C - 85°C	-40°C - 85°C
V <sub>CC</sub> Power Supply	5V ± 10%	5V ± 10%

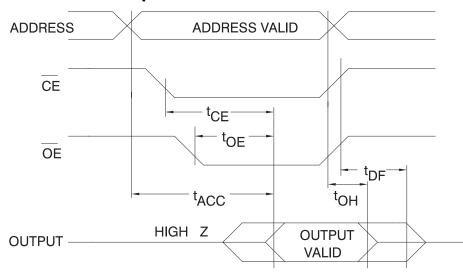
## 8. DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$		±1	μA
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$		±5	μA
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1)</sup> Read/Standby Current	$V_{PP} = V_{CC}$		10	μA
		$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC \pm} 0.3V$		100	μA
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> Standby Current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V		1	mA
I <sub>CC</sub>	V <sub>CC</sub> Active Current	$f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$		30	mA
V <sub>IL</sub>	Input Low Voltage		-0.6	0.8	V
V <sub>IH</sub>	Input High Voltage		2.0	V <sub>CC</sub> + 0.5	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V

Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously with or after  $V_{PP}$ 

2. V<sub>PP</sub> may be connected directly to V<sub>CC</sub>, except during programming. The supply current would then be the sum of I<sub>CC</sub> and I<sub>PP</sub>

# 9. AC Waveforms for Read Operation<sup>(1)</sup>



## 10. AC Characteristics for Read Operation

				AT27C516			
			-4	-45		0	
Symbol	Parameter Co	ondition	Min	Max	Min	Max	Units
t <sub>ACC</sub> <sup>(3)</sup>	Address to Output Delay CE	$\overline{E} = \overline{OE} = V_{IL}$		45		70	ns
t <sub>CE</sub> <sup>(2)</sup>	CE to Output Delay OE	$\overline{E} = V_{IL}$		45		70	ns
t <sub>OE</sub> <sup>(2)(3)</sup>	OE to Output Delay CE	Ē = V <sub>IL</sub>		20		25	ns
t <sub>DF</sub> <sup>(4)(5)</sup>	OE or CE High to Output Float, white	chever occurred first		20		25	ns
t <sub>он</sub>	Output Hold from Address, CE or O Occurred First				7		ns

Notes: 1. Timing measurement reference level is 1.5V for -45 devices. Input AC drive levels are  $V_{IL} = 0.0V$  and  $V_{IH} = 3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL} = 0.8V$  and  $V_{OH} = 2.0V$ . Input AC drive levels are  $V_{IL} = 0.45V$  and  $V_{IH} = 2.4V$ .

2.  $\overline{OE}$  may be delayed up to t<sub>CE</sub> - t<sub>OE</sub> after the falling edge of  $\overline{CE}$  without impact on t<sub>CE</sub>.

3.  $\overline{OE}$  may be delayed up to  $t_{ACC}$  -  $t_{OE}$  after the address is valid without impact on  $t_{ACC}$ .

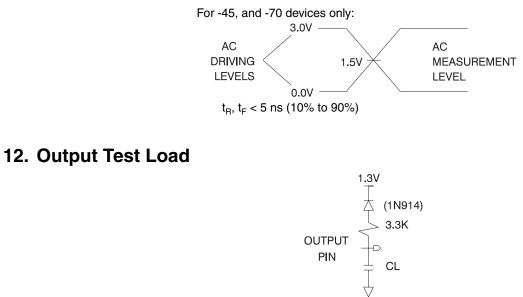
4. This parameter is only sampled and is not 100% tested.

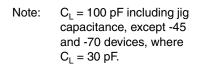
5. Output float is defined as the point when data is no longer driven.





## **11. Input Test Waveforms and Measurement Levels**





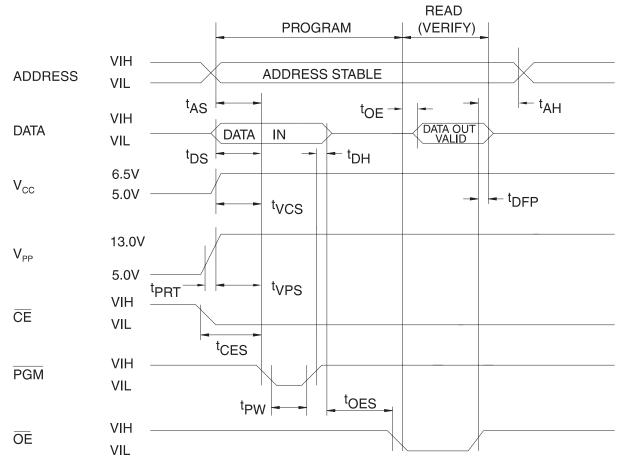
## 13. Pin Capacitance

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$ 

Symbol	Тур	Мах	Units	Conditions
C <sub>IN</sub>	4	10	pF	$V_{IN} = 0V$
C <sub>OUT</sub>	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

## 14. Programming Waveforms<sup>(1)</sup>



- Notes: 1. The Input Timing Reference is 0.8V for  $\rm V_{IL}$  and 2.0V for  $\rm V_{IH}.$ 
  - 2.  $t_{OE}$  and  $t_{DFP}$  are characteristics of the device but must be accommodated by the programmer.
  - 3. When programming the AT27C516 at 0.1  $\mu$ F capacitor is required across V<sub>PP</sub> and ground to suppress spurious voltage transients.





## **15. DC Programming Characteristics**

 $T_{A} = 25 \pm 5^{\circ}C, \, V_{CC} = 6.5 \pm 0.25V, \, V_{PP} = 13.0 \pm 0.25V$ 

			Lii	_	
Symbol	Parameter	Test Conditions	Min	Max	Units
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA
V <sub>IL</sub>	Input Low Level		-0.6	0.8	V
V <sub>IH</sub>	Input High Level		2.0	V <sub>CC</sub> + 0.1	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V
I <sub>CC2</sub>	V <sub>CC</sub> Supply Current (Program and Verify)			50	mA
I <sub>PP2</sub>	V <sub>PP</sub> Supply Current	$\overline{CE} = \overline{PGM} = V_{IL}$		30	mA
V <sub>ID</sub>	A9 Product Identification Voltage		11.5	12.5	V

## **16. AC Programming Characteristics**

 $T_A = 25 \pm 5^{\circ}C, V_{CC} = 6.5 \pm 0.25V, V_{PP} = 13.0 \pm 0.25V$ 

			Li	mit		
Symbol	Parameter	Test Conditions <sup>(1)</sup>	Min	Max	Units	
t <sub>AS</sub>	Address Setup Time		2		μs	
t <sub>CES</sub>	CE Setup Time		2		μs	
t <sub>OES</sub>	OE Setup Time	Input Rise and Fall Times:	2		μs	
t <sub>DS</sub>	Data Setup Time	(10% to 90%) 20 ns	2		μs	
t <sub>AH</sub>	Address Hold Time	Input Pulse Levels:	0		μs	
t <sub>DH</sub>	Data Hold Time	0.45V to 2.4V	2		μs	
t <sub>DFP</sub>	OE High to Output Float Delay <sup>(2)</sup>		0	130	ns	
t <sub>VPS</sub>	V <sub>PP</sub> Setup Time	Input Timing Reference Level: 0.8V to 2.0V	2		μs	
t <sub>VCS</sub>	V <sub>CC</sub> Setup Time		2		μs	
t <sub>PW</sub>	PGM Program Pulse Width <sup>(3)</sup>	Output Timing Reference Level:	47.5	52.5	μs	
t <sub>OE</sub>	Data Valid from OE	0.8V to 2.0V		150	ns	
t <sub>PRT</sub>	V <sub>PP</sub> Pulse Rise Time During Programming		50		ns	

Notes: 1. V<sub>CC</sub> must be applied simultaneously or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>

2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven – see timing diagram.

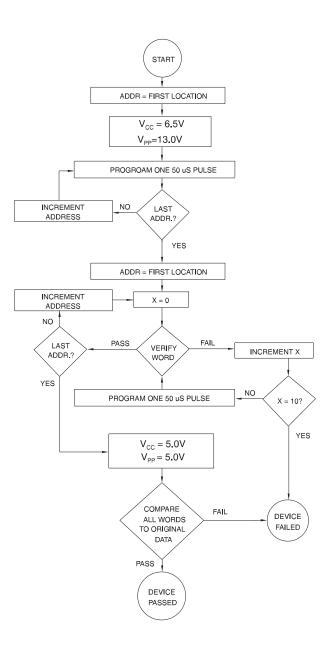
3. Program Pulse width tolerance is 50  $\mu sec \pm 5\%.$ 

## 17. Atmel's AT27C516 Integrated Product Identification Code

		Pins							Hex		
Codes	<b>A</b> 0	015-08	07	<b>O</b> 6	<b>O</b> 5	04	<b>O</b> 3	02	01	00	Data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device Type	1	0	1	1	1	1	0	0	1	0	00F2

## 18. Rapid Programming Algorithm

A 50  $\mu$ s PGM pulse width is used to program. The address is set to the first location. V<sub>CC</sub> is raised to 6.5V and V<sub>PP</sub> is raised to 13.0V. Each address is first programmed with one 50  $\mu$ s PGM pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50  $\mu$ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked. V<sub>PP</sub> is then lowered to 5.0V and V<sub>CC</sub> to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.







## **19. Ordering Information**

#### **Standard Package** 19.1

t <sub>ACC</sub>		l <sub>CC</sub> (mA)					
(ns)	ł	Active	Standby	Ordering Code	Package	<b>Operation Range</b>	
45				AT27C516-45JI	44J		
10		30	0.1	AT27C516-45VI	40V <sup>(2)</sup>	Industrial	
70	00	00 0.1	0.1	0.1	AT27C516-70JI	44J	(-40° C to 85° C)
70				AT27C516-70VI	40V <sup>(2)</sup>		
Notes:	: 1. Not recommended for new designs. Use Green package option.						

Not recommended for new designs. Use Green package option.

2. The 40-lead VSOP package is not recommended for new designs.

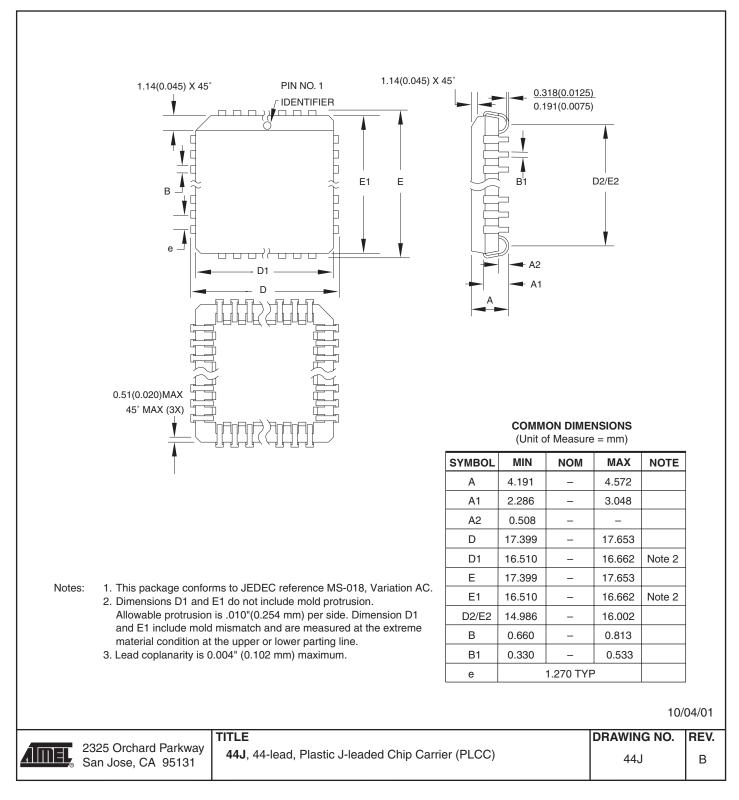
#### Green Package Option (Pb/Halide-free) 19.2

t <sub>ACC</sub>	I <sub>CC</sub> (mA)				
(ns)	Active	Standby	Ordering Code	Package	Operation Range
45	- 30	0.1	AT27C516-45JU	- 44J	Industrial (-40°C to 85°C)
70			AT27C516-70JU		

Package Type				
44J	44-lead, Plastic J-leaded Chip Carrier (PLCC)			
40V	40-lead, Plastic Thin Small Outline Package (VSOP)			

## 20. Package Information









#### 20.2 40V – VSOP

